

General Description

The WST2078 is the highest performance trench N-ch and P-ch MOSFETs with extreme high cell density, which provide excellent RDSON and gate charge for most of the small power switching and load switch applications.

The WST2078 meet the RoHS and Green Product requirement with full function reliability approved.

Features

- Advanced high cell density Trench technology
- Super Low Gate Charge
- Excellent Cdv/dt effect decline
- Green Device Available

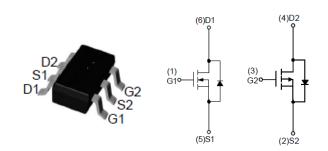
Product Summery

BVDSS	RDSON	ID
20V	30mΩ	5.6A
-20V	65mΩ	-4.5A

Applications

- High Frequency Point-of-Load Synchronous s Small power switching for MB/NB/UMPC/VGA
- Networking DC-DC Power System
- Load Switch

SOT-23-6L Pin Configuration



Absolute Maximum Ratings

		Rating		
Symbol	Parameter	N-Channel P-Channel		Units
V _{DS}	Drain-Source Voltage		-20	V
V _{GS}	Gate-Source Voltage		±12	V
I _D @T _c =25℃	Continuous Drain Current, V _{GS} @ 4.5V ¹	5.6	-4.5	А
I _D @T₀=70°C	Continuous Drain Current, V _{GS} @ 4.5V ¹	4	-2.6	А
I _{DM}	Pulsed Drain Current ²	20	-13	А
P₀@T _A =25℃	Total Power Dissipation ³	1.4	1.4	W
T _{STG}	Storage Temperature Range	-55 to 150	-55 to 150	°C
TJ	Operating Junction Temperature Range	-55 to 150	-55 to 150	°C

Thermal Data

Symbol	Parameter		Max.	Unit
R _{eja}	Thermal Resistance Junction-ambient ¹		125	°C/W
R _{θJC}	Thermal Resistance Junction-Case ¹		70	°C/W



N&P-Ch MOSFET

Symbol	Parameter	Conditions	Min.	Тур.	Max.	Unit
BV _{DSS}	Drain-Source Breakdown Voltage	V _{GS} =0V , I _D =250uA	20			V
$\triangle BV_{DSS} / \triangle T_J$	BVDSS Temperature Coefficient	Reference to 25° C , I _D =1mA		0.024		V/℃
		V _{GS} =4.5V , I _D =5A		30	38	
R _{DS(ON)}	Static Drain-Source On-Resistance ²	V _{GS} =2.5V , I _D =4A		40	54	mΩ
		V _{GS} =1.8V , I _D =1A		60	85	
V _{GS(th)}	Gate Threshold Voltage		0.5	0.7	1	V
$ riangle V_{GS(th)}$	V _{GS(th)} Temperature Coefficient	—V _{GS} =V _{DS} , I _D =250uA		-2.51		mV/℃
	Drain Course Leakana Current	V _{DS} =16V , V _{GS} =0V , T _J =25℃			1	
I _{DSS}	Drain-Source Leakage Current	V _{DS} =16V , V _{GS} =0V , T _J =55℃			5	uA uA
I _{GSS}	Gate-Source Leakage Current	$V_{GS}=\pm 8V$, $V_{DS}=0V$			±100	nA
gfs	Forward Transconductance	V _{DS} =5V , I _D =3A		10		S
R _g	Gate Resistance	V_{DS} =0V , V_{GS} =0V , f=1MHz		2.2	3.4	Ω
Qg	Total Gate Charge (4.5V)			9		
Q _{gs}	Gate-Source Charge	V _{DS} =10V , V _{GS} =10V , I _D =5A		0.3		nC
Q _{gd}	Gate-Drain Charge			2		
T _{d(on)}	Turn-On Delay Time			2.4	4.3	
Tr	Rise Time	V_{DD} =10V , V_{GEN} =4.5V , R_{G} =6 Ω		13	23	- ns
T _{d(off)}	Turn-Off Delay Time	I _D =3A R∟=10Ω		15.5	28	
T _f	Fall Time			3	5.5	
C _{iss}	Input Capacitance	V _{DS} =10V , V _{GS} =0V , f=1MHz		275		
C _{oss}	Output Capacitance			70		pF
C _{rss}	Reverse Transfer Capacitance			60		

N-Channel Electrical Characteristics (T_J=25⁻¹C, unless otherwise noted)

Drain-Source Body Diode Characteristics

Symbol	Parameter	Conditions	Min.	Тур.	Max.	Unit
Is	Continuous Source-Drain Diode Current ^{1,4}				1.0	A
I _{SM}	Pulsed Diode Forward Current ^{2,4}	V _G =V _D =0V , Force Current			20	А
V _{SD}	Body Diode Voltage ²	V _{GS} =0V , I _S =1A , T _J =25℃			1.1	V
t _{rr}	Reverse Recovery Time			10.5		nS
Q _{rr}	Reverse Recovery Charge	IF=5A,dI/dt=100A/µs,Tյ=25℃		3.2		nC

Note :

1. The data tested by surface mounted on a 1 inch² FR-4 board with 2OZ copper.

2.The data tested by pulsed , pulse width $\leq 300us$, duty cycle $\leq 2\%$ 3.The power dissipation is limited by 150 $^\circ\!C\,$ junction temperature

4. The data is theoretically the same as I_D and I_{DM} , in real applications, should be limited by total power dissipation.



N&P-Ch MOSFET

Symbol	Parameter	Conditions	Min.	Тур.	Max.	Unit
BV _{DSS}	Drain-Source Breakdown Voltage	V _{GS} =0V , I _D =-250uA	-20			V
∆BV _{DSS} /∆T _J	BVDSS Temperature Coefficient	Reference to $25^\circ\!\!\mathbb{C}$, I_D=-1mA		-0.014		V/℃
		V _{GS} =-4.5V , I _D =-3A		65	85	
R _{DS(ON)}	Static Drain-Source On-Resistance ²	V _{GS} =-2.5V , I _D =-2A		90	120	mΩ
		V _{GS} =-1.8V , I _D =-1.5A		130	210	
V _{GS(th)}	Gate Threshold Voltage		-0.3	-0.5	-1.0	V
	V _{GS(th)} Temperature Coefficient	-V _{GS} =V _{DS} , I _D =-250uA		2.3		mV/℃
		V _{DS} =-16V , V _{GS} =0V , TJ=25℃			1	– uA
I _{DSS}	Drain-Source Leakage Current	V _{DS} =-16V , V _{GS} =0V , T _J =55℃			5	
I _{GSS}	Gate-Source Leakage Current	$V_{GS}=\pm 8V$, $V_{DS}=0V$			± 100	nA
gfs	Forward Transconductance	V _{DS} =-5V , I _D =-3A		3.7		S
Qg	Total Gate Charge (-4.5V)			4.5		
Q _{gs}	Gate-Source Charge			0.5		nC
Q _{gd}	Gate-Drain Charge			1.5		
T _{d(on)}	Turn-On Delay Time			5.3		
Tr	Rise Time	V_{DD} =-10V , V_{GEN} =-10V , R_{G} =6 Ω		14.2		20
T _{d(off)}	Turn-Off Delay Time	I _D =-1A ,R∟=10Ω.		22		ns
T _f	Fall Time			4.6		
Ciss	Input Capacitance	V _{DS} =-10V , V _{GS} =0V , f=1MHz		310		
C _{oss}	Output Capacitance			66		pF
Crss	Reverse Transfer Capacitance			54		

P-Channel Electrical Characteristics (T_J=25 $^\circ$ C, unless otherwise noted)

Drain-Source Body Diode Characteristics

Symbol	Parameter	Conditions	Min.	Тур.	Max.	Unit
Is	Continuous Source-Drain Diode Current ^{1,4}				-3.3	А
I _{SM}	Pulsed Diode Forward Current ^{2,4}	$V_G = V_D = 0V$, Force Current			-13	А
V _{SD}	Body Diode Voltage ²	V _{GS} =0V , I _S =-1A , T _J =25℃			-1.1	V
t _{rr}	Reverse Recovery Time			20		nS
Q _{rr}	Reverse Recovery Charge	IF=-3.3A,dI/dt=100A/µs , Tյ=25℃		6		nC

Note :

3.The power dissipation is limited by 150 $^\circ\! \mathbb C$ junction temperature

4. The data is theoretically the same as I_D and I_{DM} , in real applications, should be limited by total power dissipation.

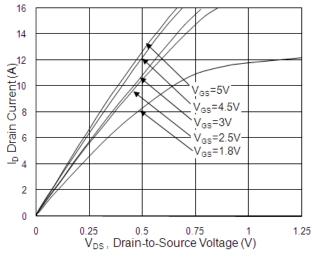
^{1.} The data tested by surface mounted on a 1 inch² FR-4 board with 2OZ copper.

^{2.}The data tested by pulsed , pulse width $\,\leq\,$ 300us , duty cycle $\,\leq\,$ 2%



N&P-Ch MOSFET

N-Channel Typical Characteristics





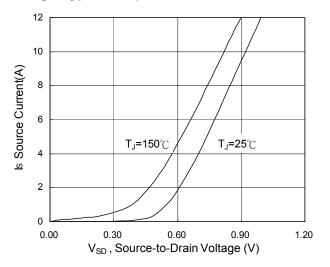


Fig.3 Forward Characteristics Of Reverse

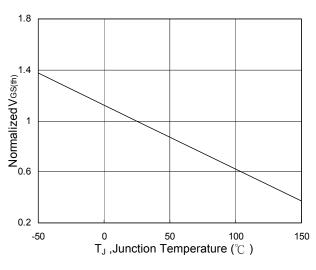


Fig.5 Normalized V_{GS(th)} vs. T_J

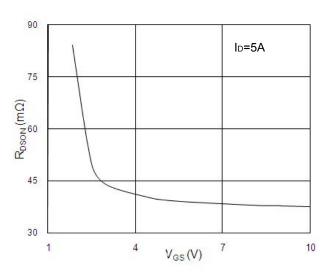


Fig.2 On-Resistance vs. Gate-Source

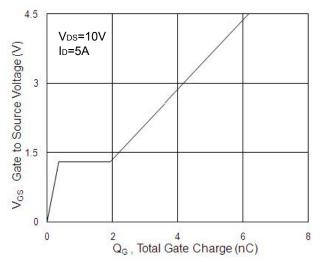


Fig.4 Gate-Charge Characteristics

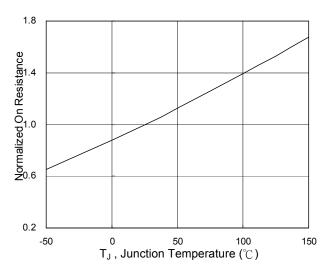


Fig.6 Normalized R_{DSON} vs. T_J



N&P-Ch MOSFET

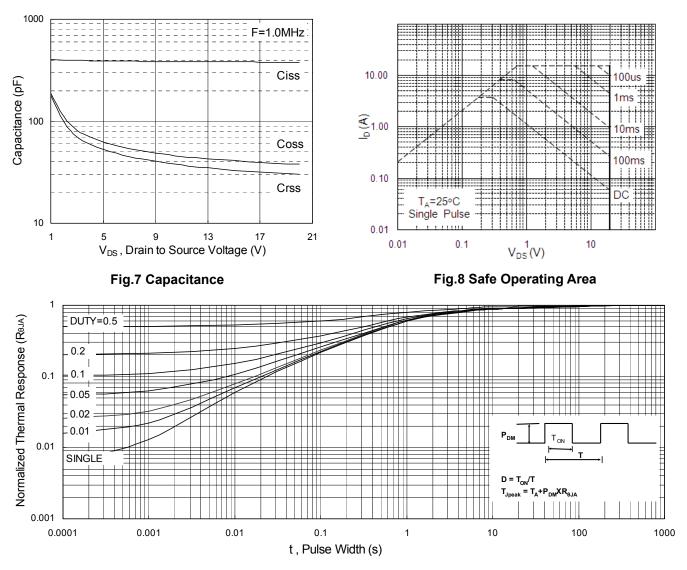
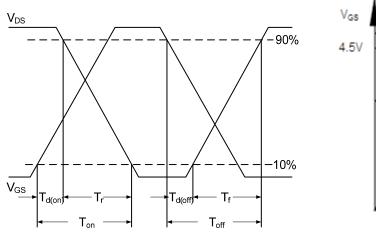
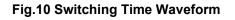


Fig.9 Normalized Maximum Transient Thermal Impedance





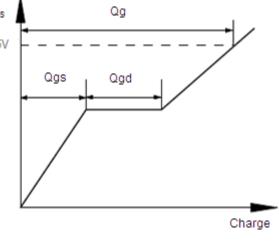
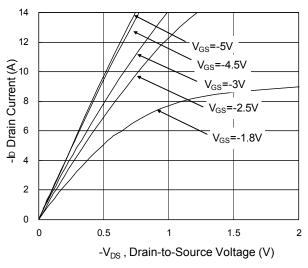


Fig.11 Gate Charge Waveform

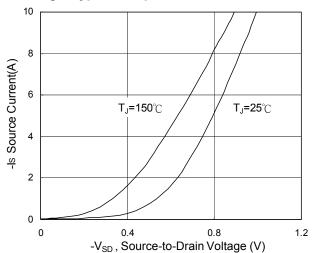


N&P-Ch MOSFET

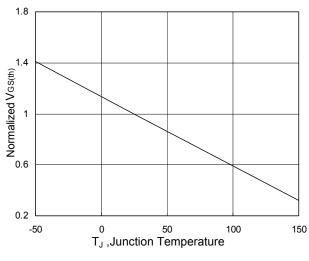
P-Channel Typical Characteristics











(°C) Fig.5 Normalized $V_{GS(th)} \, vs. \, T_J$

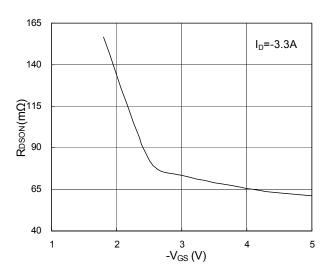


Fig.2 On-Resistance vs. Gate-Source

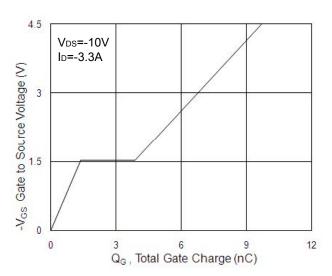


Fig.4 Gate-Charge Characteristics

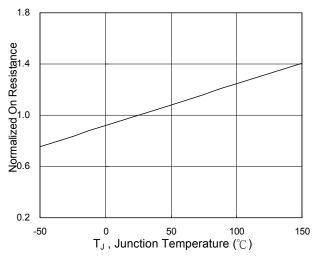


Fig.6 Normalized R_{DSON} vs. T_J



N&P-Ch MOSFET

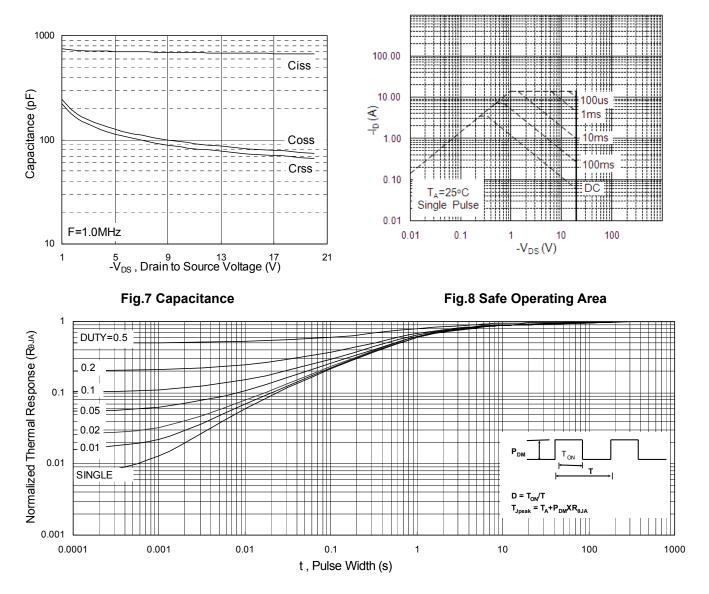


Fig.9 Normalized Maximum Transient Thermal Impedance

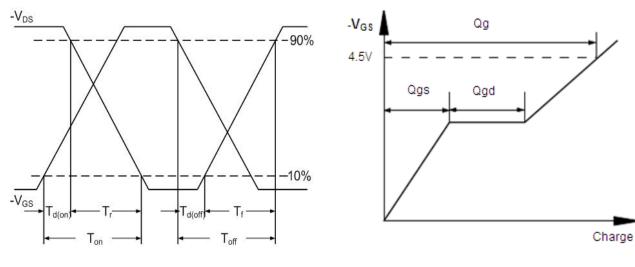




Fig.11 Gate Charge Waveform



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